VRoHS

RF Power Field Effect Transistors

N-Channel Enhancement-Mode Lateral MOSFETs

Designed for base station applications with wide instantaneous bandwidth requirements covering frequencies from 2300 to 2400 MHz.

Typical Doherty Single-Carrier W-CDMA Performance: V_{DD} = 28 Volts, I_{DQA} = 600 mA, V_{GSB} = 1.2 Vdc, P_{out} = 30 Watts Avg., IQ Magnitude Clipping, Channel Bandwidth = 3.84 MHz, Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF.

Frequency	G _{ps} (dB)	η _D (%)	Output PAR (dB)	ACPR (dBc)
2300 MHz	13.9	37.1	7.9	-31.0
2350 MHz	14.1	38.3	7.7	-32.2
2400 MHz	13.8	38.3	7.4	-33.1

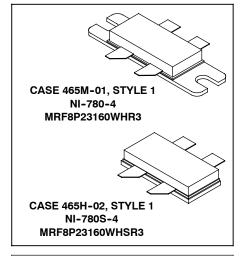
- Capable of Handling 10:1 VSWR, @ 30 Vdc, 2350 MHz, 144 Watts CW (1)
 Output Power (3 dB Input Overdrive from Rated Pout)
- Typical P_{out} @ 3 dB Compression Point ≈ 190 Watts (2)

Features

- · Designed for Wide Instantaneous Bandwidth Applications
- · Designed for Wideband Applications that Require 100 MHz Signal Bandwidth
- Production Tested in a Symmetrical Doherty Configuration
- 100% PAR Tested for Guaranteed Output Power Capability
- Characterized with Large-Signal Load-Pull Parameters and Common Source S-Parameters
- Internally Matched for Ease of Use
- · Integrated ESD Protection
- Greater Negative Gate-Source Voltage Range for Improved Class C Operation
- · Designed for Digital Predistortion Error Correction Systems
- NI-780-4 in Tape and Reel. R3 Suffix = 250 Units, 56 mm Tape Width, 13 inch Reel. For R5 Tape and Reel option, see p. 14.
- NI-780S-4 in Tape and Reel. R3 Suffix = 250 Units, 32 mm Tape Width, 13 inch Reel. For R5 Tape and Reel option, see p. 14.

MRF8P23160WHR3 MRF8P23160WHSR3

2300-2400 MHz, 30 W AVG., 28 V SINGLE W-CDMA LATERAL N-CHANNEL RF POWER MOSFETs



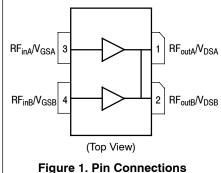


Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	-0.5, +65	Vdc
Gate-Source Voltage	V_{GS}	-6.0, +10	Vdc
Operating Voltage	V_{DD}	32, +0	Vdc
Storage Temperature Range	T _{stg}	-65 to +150	°C
Case Operating Temperature	T _C	125	°C
Operating Junction Temperature (3,4)	TJ	225	°C
CW Operation @ T _C = 25°C Derate above 25°C	CW	129 0.48	W W/°C

- 1. Exceeds recommended operating conditions. See CW operation data in Maximum Ratings table.
- 2. P3dB = P_{avg} + 7.0 dB where P_{avg} is the average output power measured using an unclipped W-CDMA single-carrier input signal where output PAR is compressed to 7.0 dB @ 0.01% probability on CCDF.
- 3. Continuous use at maximum temperature will affect MTTF.
- 4. MTTF calculator available at http://www.freescale.com/rf. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.



Table 2. Thermal Characteristics

Characteristic	Symbol	Value (1,2)	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$		°C/W
Case Temperature 80°C, 30 W CW, 28 Vdc, I_{DQA} = 600 mA, V_{GGB} = 2.4 Vdc, 2350 MHz		0.69	
Case Temperature 101°C, 130 W CW ⁽³⁾ , 28 Vdc, I _{DQA} = 600 mA, V _{GGB} = 2.4 Vdc, 2350 MHz		0.43	

Table 3. ESD Protection Characteristics

Test Methodology	Class
Human Body Model (per JESD22-A114)	2
Machine Model (per EIA/JESD22-A115)	В
Charge Device Model (per JESD22-C101)	IV

Table 4. Electrical Characteristics (T_A = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
Off Characteristics	•		•	•	•
Zero Gate Voltage Drain Leakage Current (V _{DS} = 65 Vdc, V _{GS} = 0 Vdc)	I _{DSS}	_	_	10	μAdc
Zero Gate Voltage Drain Leakage Current (V _{DS} = 28 Vdc, V _{GS} = 0 Vdc)	I _{DSS}	_	_	5	μAdc
Gate-Source Leakage Current (V _{GS} = 5 Vdc, V _{DS} = 0 Vdc)	I _{GSS}	_	_	1	μAdc
On Characteristics					
Gate Threshold Voltage (V_{DS} = 10 Vdc, I_D = 252 μ Adc)	V _{GS(th)}	1.2	1.9	2.7	Vdc
Gate Quiescent Voltage (V _{DS} = 28 Vdc, I _{DA} = 600 mAdc)	V _{GSA(Q)}	_	2.8	_	Vdc
Fixture Gate Quiescent Voltage (4,5) (V _{DD} = 28 Vdc, I _{DA} = 600 mAdc, Measured in Functional Test)	V _{GGA(Q)}	4.1	5.5	7.1	Vdc
Drain-Source On-Voltage (V _{GS} = 10 Vdc, I _D = 3.0 Adc)	V _{DS(on)}	0.1	0.24	0.3	Vdc

Functional Tests $^{(6,7,8)}$ (In Freescale Doherty Test Fixture, 50 ohm system) $V_{DD} = 28$ Vdc, $I_{DQA} = 600$ mA, $V_{GSB} = 1.2$ Vdc, $P_{out} = 30$ W Avg., f = 2320 MHz, Single-Carrier W-CDMA, IQ Magnitude Clipping, Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF. ACPR measured on 3.84 MHz Channel Bandwidth @ ± 5 MHz Offsett.

Power Gain	G _{ps}	12.0	14.1	15.0	dB
Drain Efficiency	η_{D}	32.0	36.5	_	%
Output Peak-to-Average Ratio @ 0.01% Probability on CCDF	PAR	7.2	7.8	_	dB
Adjacent Channel Power Ratio	ACPR	_	-32.2	-28.0	dBc

Typical Broadband Performance $^{(6,8)}$ (In Freescale Doherty Test Fixture, 50 ohm system) $V_{DD} = 28$ Vdc, $I_{DQA} = 600$ mA, $V_{GSB} = 1.2$ Vdc, $P_{out} = 30$ W Avg., Single-Carrier W-CDMA, IQ Magnitude Clipping, Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF. ACPR measured in 3.84 MHz Channel Bandwidth @ ± 5 MHz Offset.

Frequency	G _{ps} (dB)	η _D (%)	Output PAR (dB)	ACPR (dBc)
2300 MHz	13.9	37.1	7.9	-31.0
2350 MHz	14.1	38.3	7.7	-32.2
2400 MHz	13.8	38.3	7.4	-33.1

- 1. MTTF calculator available at http://www.freescale.com/rf. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.
- 2. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to http://www.freescale.com/rf. Select Documentation/Application Notes AN1955.
- 3. Exceeds recommended operating conditions. See CW operation data in Maximum Ratings table.
- 4. Each side of device measured separately.
- 5. V_{GG} = 2.0 x V_{GS(Q)}. Parameter measured on Freescale Test Fixture, due to resistor divider network on the board. Refer to Test Fixture Layout.
- 6. V_{DDA} and V_{DDB} must be tied together and powered by a single DC power supply.
- 7. Part internally matched both on input and output.
- 8. Measurement made with device in a Symmetrical Doherty configuration

(continued)

MRF8P23160WHR3 MRF8P23160WHSR3

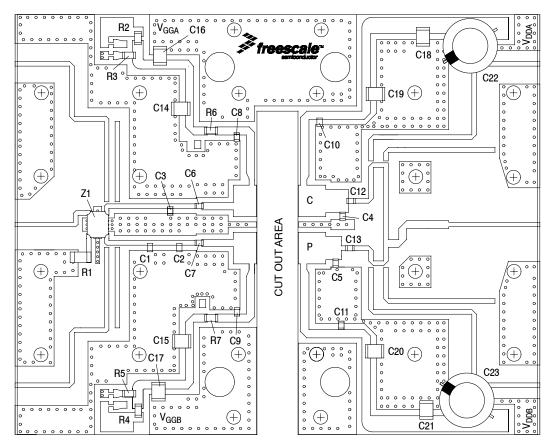
Table 4. Electrical Characteristics (T_A = 25°C unless otherwise noted) (continued)

Characteristic	Symbol	Min	Тур	Max	Unit		
Typical Performances ⁽¹⁾ (In Freescale Doherty Test Fixture, 50 ohm system) V _{DD} = 28 Vdc, I _{DQA} = 600 mA, V _{GSB} = 1.2 Vdc,							

2300-2400 MHz Bandwidth

Pout @ 1 dB Compression Point, CW	P1dB	_	150 (2)	_	W
Pout @ 3 dB Compression Point (3)	P3dB	_	190	=	W
IMD Symmetry @ 28 W PEP, P _{out} where IMD Third Order Intermodulation ≅ 30 dBc (Delta IMD Third Order Intermodulation between Upper and Lower Sidebands > 2 dB)		_	102	_	MHz
VBW Resonance Point (IMD Third Order Intermodulation Inflection Point)	VBW _{res}	_	150	_	MHz
Gain Flatness in 100 MHz Bandwidth @ P _{out} = 30 W Avg.	G _F	_	0.6	_	dB
Gain Variation over Temperature (-30°C to +85°C)	ΔG	_	0.015	_	dB/°C
Output Power Variation over Temperature (-30°C to +85°C) (2)	ΔP1dB	_	0.017	_	dB/°C

- 1. Measurement made with device in a Symmetrical Doherty configuration.
- Exceeds recommended operating conditions. See CW operation data in Maximum Ratings table.
 P3dB = P_{avg} + 7.0 dB where P_{avg} is the average output power measured using an unclipped W-CDMA single-carrier input signal where output PAR is compressed to 7.0 dB @ 0.01% probability on CCDF.



Note: V_{DDA} and V_{DDB} must be tied together and powered by a single DC power supply.

Figure 2. MRF8P23160WHR3(WHSR3) Test Circuit Component Layout

Table 5. MRF8P23160WHR3(WHSR3) Test Circuit Component Designations and Values

Part	Description	Part Number	Manufacturer
C1, C4, C5	0.2 pF Chip Capacitors	ATC600F0R2BT250XT	ATC
C2, C3	0.3 pF Chip Capacitors	ATC600F0R3BT250XT	ATC
C6	3.3 pF Chip Capacitor	ATC600F3R3BT250XT	ATC
C7	5.6 pF Chip Capacitor	ATC600F5R6BT250XT	ATC
C8, C9, C12, C13	6.8 pF Chip Capacitors	ATC600F6R8BT250XT	ATC
C10, C11	8.2 pF Chip Capacitors	ATC600F8R2BT250XT	ATC
C14, C15	330 nF, 50 V Chip Capacitors	C3225X7R2A334KT	TDK
C16, C17, C18, C19, C20, C21	10 μF, 100 V Chip Capacitors	C3225X7R2A106KT	TDK
C22, C23	220 μF, 100 V Electrolytic Capacitor	EEV-FK2A221M	Panasonic-ECG
R1	50 Ω, 10 W Chip Resistor	CW12010T0050GBK	ATC
R2, R3, R4, R5	390 Ω, 1/4 W Chip Resistors	CRCW1206390FKEA	Vishay
R6, R7	4.75 Ω, 1/4 W Chip Resistors	CRCW12064R75FKEA	Vishay
Z1	2300-2700 MHz 90°, 3 dB Chip Hybrid Coupler	1P603S	Anaren
PCB	0.020", ε _r = 3.5	RF35A2	Taconic

TYPICAL CHARACTERISTICS

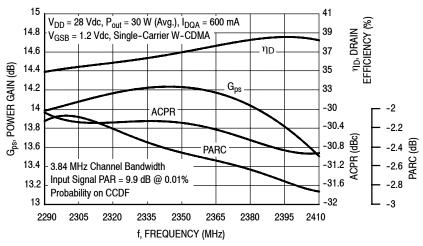


Figure 3. Single-Carrier Output Peak-to-Average Ratio Compression (PARC) Broadband Performance @ Pout = 30 Watts Avg.

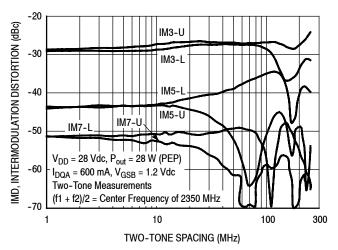


Figure 4. Intermodulation Distortion Products versus Two-Tone Spacing

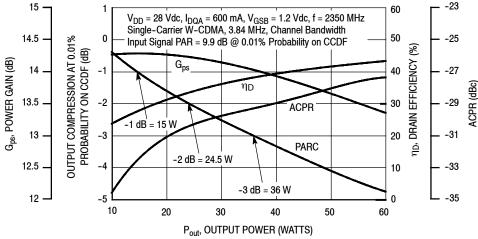


Figure 5. Output Peak-to-Average Ratio Compression (PARC) versus Output Power

TYPICAL CHARACTERISTICS

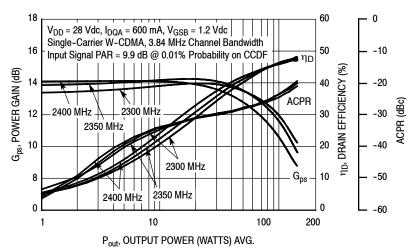


Figure 6. Single-Carrier W-CDMA Power Gain, Drain Efficiency and ACPR versus Output Power

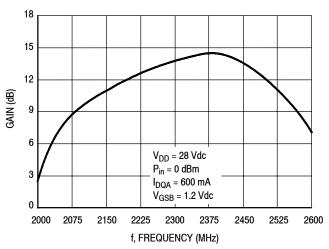


Figure 7. Broadband Frequency Response

W-CDMA TEST SIGNAL

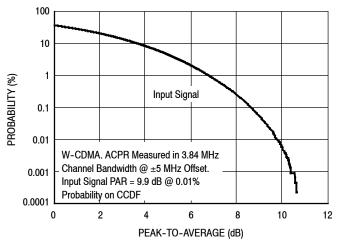


Figure 8. CCDF W-CDMA IQ Magnitude Clipping, Single-Carrier Test Signal

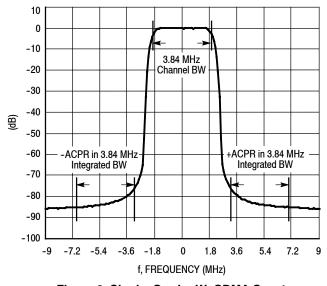


Figure 9. Single-Carrier W-CDMA Spectrum

 V_{DD} = 28 Vdc, I_{DQA} = 600 mA, Pulsed CW, 10 μ sec(on), 10% Duty Cycle

			Max Output Power					
f	Z _{source}	Z _{load} (1)	P1dB				P3dB	
(MHz)	(Ω)	(Ω)	(dBm)	(W)	η _D (%)	(dBm)	(W)	η _D (%)
2300	15.8 - j13.8	5.58 - j10.3	49.8	95	47.6	50.8	121	57.1
2350	19.8 - j7.63	5.70 - j10.4	49.7	93	48.2	50.7	119	56.1
2400	16.0 + j0.38	5.96 - j10.5	49.7	92	49.0	50.7	118	55.8

⁽¹⁾ Load impedance for optimum P1dB power.

 Z_{source} = Impedance as measured from gate contact to ground. Z_{load} = Impedance as measured from drain contact to ground.

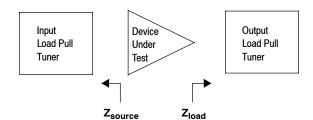


Figure 10. Carrier Side Load Pull Performance — Maximum P1dB Tuning

 V_{DD} = 28 Vdc, I_{DQA} = 600 mA, Pulsed CW, 10 $\mu sec(on),\,10\%$ Duty Cycle

			Max Drain Efficiency					
f	Z _{source}	Z _{load} (1)	P1dB				P3dB	
(MHz)	(Ω)	(Ω)	(dBm)	(W)	η _D (%)	(dBm)	(W)	η _D (%)
2300	15.8 - j13.8	6.54 - 4.70	48.3	67	57.1	49.6	91	59.4
2350	19.8 - j7.63	5.70 - 5.65	48.3	68	56.1	49.4	86	58.5
2400	16.0 + j0.38	5.50 - 6.23	48.3	68	55.8	49.7	92	58.0

⁽¹⁾ Load impedance for optimum P1dB efficiency.

 Z_{source} = Impedance as measured from gate contact to ground.

Z_{load} = Impedance as measured from drain contact to ground.

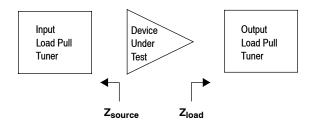
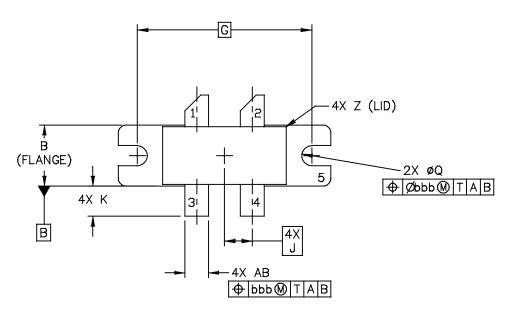
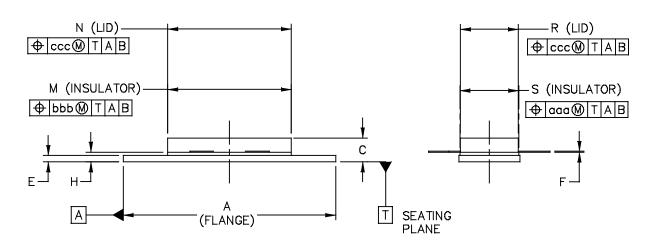


Figure 11. Carrier Side Load Pull Performance — Maximum Drain Efficiency Tuning

PACKAGE DIMENSIONS





© FREESCALE SEMICONDUCTOR, INC. ALL RIGHTS RESERVED.	MECHANICAL OU	JTLINE	PRINT VERSION NO	T TO SCALE	
TITLE:	DOC	CUMENT NO): 98ASA10793D	REV: 0	
NI 780-4	CAS	SE NUMBER	: 465M-01	27 MAR 2007	
	STA	NDARD: NO	N-JEDEC		

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1994.
- 2. CONTROLLING DIMENSION: INCH.
- 3. DIMENSION H IS MEASURED . 030 (0.762) AWAY FROM PACKAGE BODY.

STYLE 1:

PIN 1. DRAIN

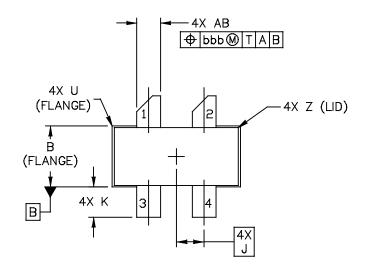
2. DRAIN

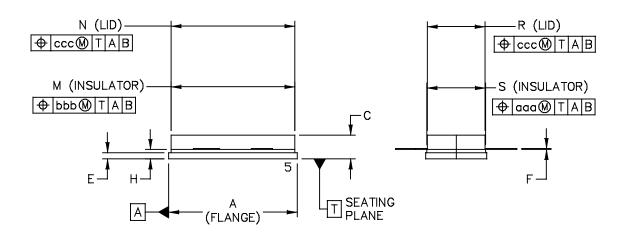
3. GATE

4. GATE

5. SOURCE

	INCH		MILLIMETER			INCH		MILLIMETER		
DIM	MIN	MAX	MIN	MAX	DIM	MIN MAX		MIN	MAX	
Α	1.335	1.345	33.91	34.16	R	.365	.375	9.2	7 9.53	
В	.380	.390	9.65	9.91	S	.365	.375	9.2	7 9.52	
С	.125	.170	3.18	4.32	U		.040		1.02	
E	.035	.045	0.89	1.14	Z		.030		0.76	
F	.003	.006	0.08	0.15	AB	. 145	. 155	3. 68	3. 94	
G	1. 100	BSC	27.	94 BSC						
Н	.057	.067	1.45	1.7	aaa	.005		0.127		
J	. 175	BSC	4. 4	44 BSC	bbb	.010		0.254		
K	.170	.210	4.32	5.33	ccc	.015		0.381		
М	.774	.786	19.61	20.02						
N	.772	.788	19.61	20.02						
Q	ø.118	ø.138	ø3	ø3.51						
© FREESCALE SEMICONDUCTOR, INC. ALL RIGHTS RESERVED. MEC			MECHANICA	L OUTLINE PRINT VERS			SION NOT TO SCALE			
TITLE:					DOCU	DOCUMENT NO: 98ASA10793D REV: 0				
NI 780-4					CASE NUMBER: 465M-01 27 MAR				27 MAR 2007	
					STANDARD: NON-JEDEC					





© FREESCALE SEMICONDUCTOR, INC. ALL RIGHTS RESERVED.	MECHANICAL OUTLINE		PRINT VERSION NOT TO SCALE		
TITLE:		DOCUMENT NO): 98ASA10718D	REV: A	
NI 780S-4		CASE NUMBER	:: 465H-02	27 MAR 2007	
		STANDARD: NO	N-JEDEC		

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1994.
- 2. CONTROLLING DIMENSION: INCH.
- 3. DELETED
- 4. DIMENSION H IS MEASURED . 030 (0.762) AWAY FROM PACKAGE BODY.

STYLE 1:

PIN 1. DRAIN

2. DRAIN

3. GATE

4. GATE

5. SOURCE

	IN	INCH MILLIMETER				INCH		MILLIMETER			
DIM	MIN	MAX	MIN	MAX	DIM	MIN	MAX	MIN	1	MAX	
A	.805	.815	20.45	20.7	U		.040			1.02	
В	.380	.390	9.65	9.91	Z		.030			0.76	
С	.125	.170	3.18	4.32	AB	. 145	. 155	3.6	8 –	3. 94	
E	.035	.045	0.89	1.14							
F	.003	.006	0.08	0.15	aaa		.005		0.127		
Н	.057	.067	1.45	1.7	bbb		.010	0.254			
J	. 175	BSC	4.	44 BSC	ccc	.015		0.381			
K	.170	.210	4.32	5.33							
М	.774	.786	19.61	20.02							
N	.772	.788	19.61	20.02							
R	.365	.375	9.27	9.53							
S	.365	.375	9.27	9.52							
© FREESCALE SEMICONDUCTOR, INC. ALL RIGHTS RESERVED. MECHA				MECHANICA	L OUTLINE PRINT VERS			SION NOT TO SCALE			
TITLE:					DOCUMENT NO: 98ASA10718D			REV:	A		
NI 780S-4					CASE NUMBER: 465H-02 27 MAR				AR 2007		
				STANDARD: NON-JEDEC							

PRODUCT DOCUMENTATION, SOFTWARE AND TOOLS

Refer to the following documents, software and tools to aid your design process.

Application Notes

• AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Engineering Bulletins

• EB212: Using Data Sheet Impedances for RF LDMOS Devices

Software

- Electromigration MTTF Calculator
- · RF High Power Model
- .s2p File

For Software and Tools, do a Part Number search at http://www.freescale.com, and select the "Part Number" link. Go to the Software & Tools tab on the part's Product Summary page to download the respective tool.

R5 TAPE AND REEL OPTION

R5 Suffix = 50 Units, 56 mm Tape Width, 13 inch Reel.

The R5 tape and reel option for MRF8P23160WH and MRF8P23160WHS parts will be available for 2 years after release of MRF8P23160WH and MRF8P23160WHS. Freescale Semiconductor, Inc. reserves the right to limit the quantities that will be delivered in the R5 tape and reel option. At the end of the 2 year period customers who have purchased these devices in the R5 tape and reel option will be offered MRF8P23160WH and MRF8P23160WHS in the R3 tape and reel option.

REVISION HISTORY

The following table summarizes revisions to this document.

Revision	Date	Description
0	Dec. 2011	Initial Release of Data Sheet

How to Reach Us:

Home Page:

www.freescale.com

Web Support:

http://www.freescale.com/support

USA/Europe or Locations Not Listed:

Freescale Semiconductor, Inc.
Technical Information Center, EL516
2100 East Elliot Road
Tempe, Arizona 85284
1-800-521-6274 or +1-480-768-2130
www.freescale.com/support

Europe, Middle East, and Africa:

Freescale Halbleiter Deutschland GmbH Technical Information Center Schatzbogen 7 81829 Muenchen, Germany +44 1296 380 456 (English) +46 8 52200080 (English) +49 89 92103 559 (German) +33 1 69 35 48 48 (French) www.freescale.com/support

Japan:

Freescale Semiconductor Japan Ltd. Headquarters ARCO Tower 15F 1-8-1, Shimo-Meguro, Meguro-ku, Tokyo 153-0064 Japan 0120 191014 or +81 3 5437 9125 support.japan@freescale.com

Asia/Pacific:

Freescale Semiconductor China Ltd. Exchange Building 23F No. 118 Jianguo Road Chaoyang District Beijing 100022 China +86 10 5879 8000 support.asia@freescale.com

For Literature Requests Only:

Freescale Semiconductor Literature Distribution Center 1-800-441-2447 or +1-303-675-2140 Fax: +1-303-675-2150 LDCForFreescaleSemiconductor@hibbertgroup.com

Information in this document is provided solely to enable system and software implementers to use Freescale Semiconductor products. There are no express or implied copyright licenses granted hereunder to design or fabricate any integrated circuits or integrated circuits based on the information in this document.

Freescale Semiconductor reserves the right to make changes without further notice to any products herein. Freescale Semiconductor makes no warranty, representation or quarantee regarding the suitability of its products for any particular purpose, nor does Freescale Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. "Typical" parameters that may be provided in Freescale Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals", must be validated for each customer application by customer's technical experts. Freescale Semiconductor does not convey any license under its patent rights nor the rights of others. Freescale Semiconductor products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the Freescale Semiconductor product could create a situation where personal injury or death may occur. Should Buyer purchase or use Freescale Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold Freescale Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that Freescale Semiconductor was negligent regarding the design or manufacture of the part.

Freescale [™] and the Freescale logo are trademarks of Freescale Semiconductor, Inc. All other product or service names are the property of their respective owners. © Freescale Semiconductor, Inc. 2011. All rights reserved.



Document Number: MRF8P23160WH

Rev. 0, 12/2011